



S/N/10/824,285

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Bradley M. Ratliff	Examiner:	Marcus H. Taningco
Serial No.:	10/824,285	Group Art Unit:	2884
Filed:	April 14, 2004	Docket:	1863.070US1
Title:	UNIFORM, NON-DISRUPTIVE, AND RADIOMETRICALLY ACCURATE CALIBRATION OF INFRARED FOCAL PLANE ARRAYS USING GLOBAL SCENE MOTION		

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicant respectfully requests that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicant requests that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicant with the next official communication.

Pursuant to 37 C.F.R. § 1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement. However, if an Office Action on the merits has been mailed, the Commissioner is hereby authorized to charge the required fees to Deposit Account No. 19-0743 in order to have this Information Disclosure Statement considered.

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The Examiner is invited to contact the Applicant's Representative at the below-listed telephone number if there are any questions regarding this communication.


Pursuant to 37 C.F.R. 1.98(a)(2), Applicant believes that copies of cited U.S. Patents and Published Applications are no longer required to be provided to the Office. Notification of this change was provided in the United States Patent and Trademark Office OG Notices dated October 12, 2004. Thus, Applicant has not included copies of any US Patents or Published Applications cited with this submission. Should the Office require copies to be provided, Applicant respectfully requests that notice of such requirement be directed to Applicant's below-signed representative. Applicant acknowledges the requirement to submit copies of foreign patent documents and non-patent literature in accordance with 37 C.F.R. 1.98(a)(2).

Respectfully submitted,

BRADLEY M. RATLIFF

By his Representatives,

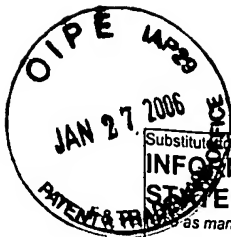
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Date 24 January 2006 By 
David R. Cochran
Reg. No. 46,632

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: MS RCE, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 24th day of January, 2006.

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Name


Signature



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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(as many sheets as necessary)

Complete if Known

Application Number	10/824,285
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First Named Inventor	Ratliff, Bradley
Group Art Unit	2884
Examiner Name	Taningco, Marcus

Sheet 1 of 6

Attorney Docket No: 1863.070US1

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	Complete if Known <table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 40%;">Application Number</td> <td>10/824,285</td> </tr> <tr> <td>Filing Date</td> <td>April 14, 2004</td> </tr> <tr> <td>First Named Inventor</td> <td>Ratliff, Bradley</td> </tr> <tr> <td>Group Art Unit</td> <td>2884</td> </tr> <tr> <td>Examiner Name</td> <td>Taningco, Marcus</td> </tr> </table>	Application Number	10/824,285	Filing Date	April 14, 2004	First Named Inventor	Ratliff, Bradley	Group Art Unit	2884	Examiner Name	Taningco, Marcus
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Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional) ² Applicant is to place a check mark here if English language Translation is attached

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